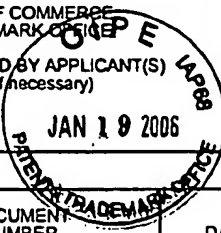


FORM PTO 1449 (modified)				ATTY DOCKET NO. 03560.003310		APPLICATION NO. 10/601,777	
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				APPLICANT Tadashi Okamoto et al.			
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				FILING DATE June 24, 2003		GROUP 1631	
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
8DJ 11/28/2006 CA TES	5,589,685	12/31/96	Jen Wu et al.	250	282		
	6,002,128	12/14/99	Hill et al.	250	287		
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	5,821,060	10/13/98	Arlinghaus et al.	435	6		
	2002/0074517 A1	06/20/02	Krutchinsky et al.	250	492.1		
	4,983,831	01/08/91	Migeon et al.	250	309		
FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT	
DUPL CA TES	DE	31 44 604 A1	05/19/83	Germany		Abstract	
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
	Steven M. Hues et al., "A Pulsed Alkali-Ion Gun for Time-of-Flight Secondary Ion Mass Spectrometry," 69(7) Rev. Sci. Instrum. 1239-44 (July 1989).						
	Viswanatham Katta et al., "A Pulsed Ion Bombardment Time-of-Flight Mass Spectrometer with High Sensitivity for the Analysis of Peptides," 105 Int. J. Mass Spectrom. Ion Processes 129-45 (1991).						
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	Robert W. Odom, "Secondary Ion Mass Spectrometry Imaging," 29(1) Appl. Spectros. Rev. 67-116 (February 1994).						
EXAMINER				DATE CONSIDERED			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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<div style="text-align: center;">  </div>		APPLICANT Tadashi Okamoto et al.				
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	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)						
ED		G.C. Rider et al., "Imaging Time-of-Flight SIMS - A New Technique for Spatially-Resolved Chemical Surface Analysis," 4(1) J. Molecul. Electron. 402 (1988) (Abstract).				
ED		Anthony J. Nicola et al., "Enhancement of Ion Intensity in Time-of-Flight Secondary-Ionization Mass Spectrometry," 7 J. Am. Soc. Mass Spectrom. 467-71 (1996).				
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				11/28/2006		

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